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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Complete if Known

Sheet	1	of	1	Application No.:	10/549,863
				Filing Date:	December 8, 2006
				First Named Inventor:	Nigel P. Smith
				Art Unit:	2823
				Examiner Name:	William D. Coleman
				Attorney Docket No.:	NAN154 US 8026

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear (if known)
		Number-Kind Code (if known)			
	1.	2001/0019401-A1	09-06-2001	Irie et al.	
	2.	4,343,878	08-10-1982	Chiang	
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	6.	EP-0 534 720-A1, B1	03-31-1993	Levien		
	7.	EP-0 818 814-A2, A3	01-14-1998	KLA Instruments Corporation		
	8.	JP-11-191530-A	07-13-1999	Mitutoyo Corporation	Translation of Abstract	
	9.	WO-02/18871-A1	03-07-2002	KLA-Tencor Corporation		
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	11.	WO-2004/090978-A2, A3	10-21-2004	AOTI Operating Company, Inc.		
	12.	WO-2004/090979-A2, A3	10-21-2004	AOTI Operating Company, Inc.		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	13.	IBM Corp. (March 1990). "Interferometric Method of Checking the Overlay Accuracy in Photolitho-Graphic Exposure Processes," <i>IBM Technical Disclosure Bulletin</i> 32(10B):214-217.	
	14.	International Search Report mailed on October 15, 2004 for PCT Application No. PCT/GB2004/001533 filed on April 8, 2004 by AOTI Operating Company, Inc, 4 pages.	
	15.	International Preliminary Report on Patentability and Written Opinion mailed on October 14, 2005 for PCT Application No. PCT/GB2004/001533 filed on April 8, 2004 by AOTI Operating Company, Inc., 7 pages.	
	16.	Smith, Nigel P. et al. (August 1993). "Minimising Optical Overlay Measurement Errors," <i>Integrated Circuit Metrology, Inspection, and Process Control VII. Proceedings of SPIE</i> 1926:450-462.	

Examiner Signature:		Date Considered:	
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* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.